

Notice of References Cited

Application/Control No.

10/042,929

Applicant(s)/Patent Under
Reexamination
NEWMAN ET AL.

Examiner

Allen C. Ho

Art Unit

2882

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,468,346 B2	10-2002	Arnowitz et al.	117/68
	B	US-6,285,736 B1	09-2001	Dosho	378/79
	C	US-6,205,199 B1	03-2001	Polichar et al.	378/98.8
	D	US-6,163,592	12-2000	He et al.	378/71
	E	US-5,737,385	04-1998	Prevey, III et al.	378/71
	F	US-5,636,258	06-1997	Okumura et al.	378/73
	G	US-5,629,524	05-1997	Stettner et al.	250/370.09
	H	US-5,491,738	02-1996	Blake et al.	378/71
	I	US-5,359,640	10-1994	Fink et al.	378/79
	J	US-5,046,077	09-1991	Murayama	378/80
	K	US-4,821,303	04-1989	Fawcett et al.	378/80
	L	US-4,634,490	01-1987	Tatsumi et al.	117/14
	M	US-3,992,624	11-1976	Flannery et al.	378/74

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	B. D. Cullity. Elements of X-Ray Diffraction, second edition (Reading, MA: Addison-Wesley, 1978).
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.